

S8X5ECSx HF ROHS



Description

The S8X5ECSx offers a high static dv/dt with a low turn off (tq) time. It is specifically designed for GFCI (Ground Fault Circuit Interrupter) and AFCI (Arc Fault Circuit Interrupter), RCD (Residual Current Device) and RCBO (Residual Current Circuit Breaker with Overload Protection) applications. All SCR junctions are glass-passivated to ensure long term reliability and parametric stability.

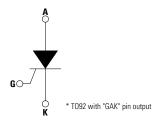
Main Features

Symbol	Value	Unit
I _{T(RMS)}	0.5	А
V_{DRM}/V_{RRM}	800	V
V_{DSM} (t _p = 50 µs)	1250	V
$V_{RSM}(t_p = 50 \mu s)$	900	V
I _{GT}	20 to 100	μА

Features

- Thru-hole packages
- Surge current capability < 20Amps
- Blocking voltage (V_{DRM} / V_{RRM}) capability - up to 800V
- Non-repetitive direct surge peak off-state voltage (V_{DSM}) up to 1250V
- Non-repetitive reverse surge peak off-state voltage (V_{RSM}) up to 900V
- High dv/dt noise immunity
- Improved turn-off time (t_a)
- Sensitive gate for direct microprocessor interface
- Halogen free and RoHS compliant

Schematic Symbol



Absolute Maximum Ratings

Symbol	Parameter	Value	Unit		
I _{T(RMS)}	RMS on-state current (full sine wave)		$T_{c} = 85^{\circ}C$	0.5	А
I _{T(AV)}	Average on-state current		$T_{c} = 85^{\circ}C$	0.3	Α
	Non repetitive surge peak on-state current		F= 50Hz	10	А
I _{TSM}	(Sine half wave, T _J initial = 25°C)		F= 60Hz	12	А
l²t	I ² t Value for fusing	t _p = 10 ms	F = 50 Hz	0.5	A ² s
di/dt	Critical rate of rise of on-state current I _G = 10mA		T _J = 125°C	80	A/µs
I _{GM}	Peak Gate Current	t _p = 20 μs	T _J = 125°C	0.5	А
P _{G(AV)}	Average gate power dissipation	_	T _J = 125°C	0.2	W
T _{stq}	Storage junction temperature range	_	_	-40 to 150	°C
T,	Operating junction temperature range	_	_	-40 to 125	°C

Thyristors

Electrical Characteristics (T_J = 25°C, unless otherwise specified)

Comphal	Description	Test Conditions Limit	l innie	Value		Unit
Symbol	Description	lest Conditions	Limit	S8X5ECS	S8X5ECS2	Onit
1	DC Gate Trigger Current	V _D = 6V	Min.	20	20	μΑ
I _{GT}	De date migger current	$R_L = 100 \Omega$	Max.	100	50	μΑ
$V_{\rm GT}$	DC Gate Trigger Voltage	$V_D = 6V$ $R_L = 100 \Omega$	Max.	0	0.8	
V _{GRM}	Peak Reverse Gate Voltage	$I_{RG} = 10\mu A$	Min.		8	V
I _H	Holding Current	$R_{GK} = 1 \text{ K}\Omega$ Initial Current = 20mA	Max.	;	3	mA
dv/dt	Critical Rate-of-Rise of Off-State Voltage	$\begin{array}{c} T_{_J} = 125^{\circ}\text{C} \\ V_{_D} = 67\% \text{ of } V_{_{DRM}} \\ \text{Exp. Waveform} \\ R_{_{GK}} = 1 k\Omega \end{array}$	Min.	4	40	
$V_{\sf GD}$	Gate Non-Trigger Voltage	$V_{D} = 1/2 V_{DRM}$ $R_{GK} = 1 k\Omega$ $T_{J} = 125^{\circ}C$	Min.	0	0.2	
t _q	Turn-Off Time	I _T = 0.5A	Max.	3	35	
t _{gt}	Turn-On Time	I _G =10mA P _W = 15μsec I _T = 1.6A(pk)	Тур.	2.3		μs

Static Characteristics (T_J = 25°C, unless otherwise specified)

Symbol	Description	Test Conditions	Limit	Value	Unit
V _{TM}	Peak On-State Voltage	0.5A device I _{TM} = 4A t _p = 380 μs	MAX.	1.8	V
V _{T0}	Threshold Voltage	-	MAX	1.03	V
$R_{_{D}}$	Dynamic Resistance	-	MAX	106	mΩ
I _{DRM} / I _{RRM}	Off-State Current, Peak Repetitive	T _J = 25°C	$_{\rm TM} = 4 {\rm A} {\rm t_p} = 380 {\rm \mu s}$ MAX. 1 MAX 1. T _J = 25°C MAX.	3	μА
	On-State Current, Peak Repetitive	T _J = 125°C		500	μА

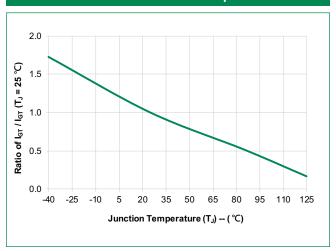
Thermal Resistances

Symbol	Description	Test Conditions	Value	Unit
R _{th(JC)}	Junction to case (AC)	$I_{T} = 0.8A_{(RMS)}^{1}$	35	°C/W
R _{th(i-a)}	Junction to ambient	$I_{T} = 0.8A_{(BMS)}^{-1}$	150	°C/W

^{1. 60}Hz AC resistive load condition, 100% conduction.



Figure 1: Normalized DC Gate Trigger Current For All Quadrants vs. Junction Temperature



1.0

2.0

Ratio of $I_H/I_H(T_J = 25$ °C) 1.5 0.5 0.0 -40 -25 -10 20 35 50 65 80 95 110 125 Junction Temperature (T_J) -- (°C)

Figure 3: Normalized DC Gate Trigger Voltage vs. Junction Temperature

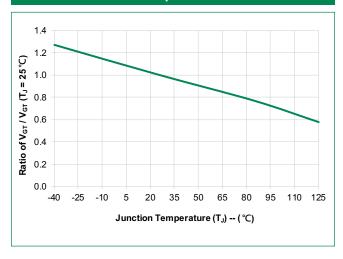


Figure 4: On-State Current vs. On-State Voltage (Typical)

Figure 2: Normalized DC Holding Current

vs. Junction Temperature

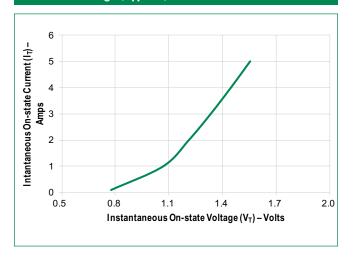


Figure 5: Power Dissipation (Typical) vs. RMS On-State Current

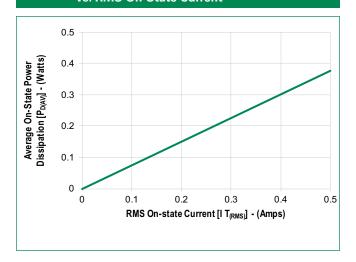


Figure 6: Maximum Allowable Case Temperature vs. On-State Current

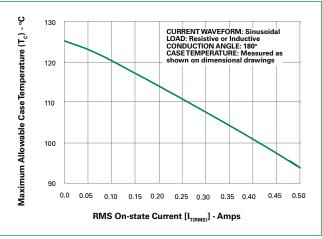
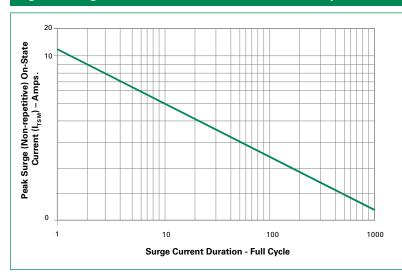


Figure 7: Surge Peak On-State Current vs. Number of Cycles



Supply Frequency: 60Hz Sinusoidal Load: Resistive

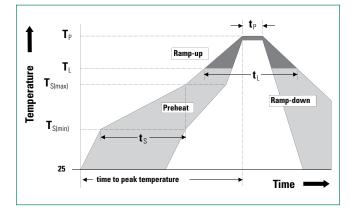
RMS On-State Current [I $_{\rm T(RMS)}$]: Max Rated Value at Specific Case Temperature

Notes:

- 1. Gate control may be lost during and immediately following surge current interval.
- 2. Overload may not be repeated until junction temperature has returned to steady-state rated value.

Soldering Parameters

Reflow Condition Pb – Free		Pb – Free assembly	
	-Temperature Min (T _{s(min)})	150°C	
Pre Heat	-Temperature Max (T _{s(max)})	200°C	
	-Time (min to max) (t _s)	60 – 180 secs	
Average ram	p up rate (Liquidus Temp) (T _L) to peak	5°C/second max	
T _{S(max)} to T _L -	Ramp-up Rate	5°C/second max	
Reflow	-Temperature (T _L) (Liquidus)	217°C	
nellow	-Time (min to max) (t _s)	60 – 150 seconds	
Peak Temperature (T _P)		260 ^{+0/-5} °C	
Time within	5°C of actual peak Temperature ($t_{_{p}}$)	20 - 40 seconds	
Ramp-down	Rate	5°C/second max	
Time 25°C to peak Temperature (T _p)		8 minutes Max.	
Do not exce	Do not exceed		



Thyristors

Physical Specifications

Terminal Finish	sh 100% Matte Tin-plated.		
Body Material	UL Recognized compound meeting flammability rating V-0.		
Lead Material	Copper Alloy		

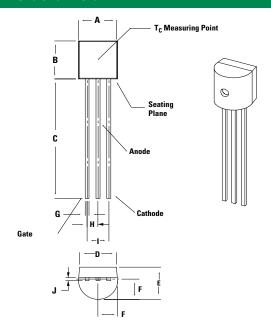
Design Considerations

Careful selection of the correct component for the application's operating parameters and environment will go a long way toward extending the operating life of the Thyristor. Good design practice should limit the maximum continuous current through the main terminals to 75% of the component rating. Other ways to ensure long life for a power discrete semiconductor are proper heat sinking and selection of voltage ratings for worst case conditions. Overheating, overvoltage (including dv/dt), and surge currents are the main killers of semiconductors. Correct mounting, soldering, and forming of the leads also help protect against component damage.

Reliability/Environmental Tests

Test	Specifications and Conditions	
AC Blocking	MIL-STD-750, M-1040, Cond A Applied Peak AC voltage @ 125°C for 1008 hours	
Temperature Cycling	voling MIL-STD-750, M-1051, 1000 cycles; -55°C to +150°C; 15-min dwell-ti	
Temperature/Humidity	EIA / JEDEC, JESD22-A101 1008 hours; 320V - DC: 85°C; 85% rel humidity	
UHAST	JESD22-A118, 96 hours, 130°C, 85%RH	
High Temp Storage	MIL-STD-750, M-1031,1008 hours; 150°C	
Low-Temp Storage	1008 hours; -40°C	
Resistance to Solder Heat	MIL-STD-750 Method 2031	
Solderability	ANSI/J-STD-002, category 3, Test A	
Lead Bend	MIL-STD-750, M-2036 Cond E	

Dimensions - TO-92



Dimension	Inc	hes	Millin	neters
Dimension	Min	Max	Min	Max
Α	0.175	0.205	4.450	5.200
В	0.170	0.210	4.320	5.330
С	0.500		12.70	
D	0.135		3.430	
E	0.125	0.165	3.180	4.190
F	0.080	0.105	2.040	2.660
G	0.016	0.021	0.407	0.533
Н	0.045	0.055	1.150	1.390
1	0.095	0.105	2.420	2.660
J	0.015	0.020	0.380	0.500

Packing Option

Part Number	Marking	Weight	Packing Mode	Base Quantity
S8X5ECS	S8X5ECS	0.217G	Bulk	2500
S8X5ECSRP	S8X5ECS	0.217G	Tape & Reel	2000
S8X5ECSAP	S8X5ECS	0.217G	Ammo Pack	2000
S8X5ECS2	S8X5ECS2	0.217G	Bulk	2500
S8X5ECS2RP	S8X5ECS2	0.217G	Tape & Reel	2000
S8X5ECS2AP	S8X5ECS2	0.217G	Ammo Pack	2000